

Notice of References Cited	Application/Control No. 10/725,133	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-6,201,273	03-2001	Wang et al.	257/306
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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